

MILITARY SPECIFICATION
CV 7490-91

SEMICONDUCTOR DEVICE, TRANSISTOR

Description:- This specification covers the detailed requirements for NPN Silicon Planar Transistors which may be used in amplifying circuits at high frequencies and is in accordance with Specification K1007, Issue 3, except where otherwise stated.

Mechanical Dimensions and Outlines:- K1007, Section B 10.3.1., CV-A 10.3.2.2., 10.4.1., 10.4.2.2. (Note 1).
CV-B 10.3.2.4., 10.4.1., 10.4.2.4.

Connections:- Collector connected to case.
Lead 1. Emitter, Lead 2. Base, Lead 3. Collector.

Absolute Maximum Ratings:-

CV-7490

RATING	V _{CB}	V _{CE}	V _{EB}	I _C mean	I _C peak	I _B mean	I _B peak	I _E mean	I _E peak	P _{tot}	T _{stg}	T _j	Shock	Vib.
Unit	V	V	V	mA	mA	mA	mA	mA	mA	W	°C	°C	g	g
Min	-	-	-	-	-	-	-	-	-	-	-55	-55	-	-
Max	40	24	3	100	200	100	200	100	200	0.6	+175	+175	1500	20
Note				A ₁	A ₂	A ₁	A ₂	A ₁	A ₂	B				

CV-7491

RATING	V _{CB}	V _{CE}	V _{EB}	I _C mean	I _C peak	I _B mean	I _B peak	I _E mean	I _E peak	P _{tot}	T _{stg}	T _j	Shock	Vib.
Unit	V	V	V	mA	mA	mA	mA	mA	mA	W	°C	°C	g	g
Min	-	-	-	-	-	-	-	-	-	-	-55	-55	-	-
Max	40	24	3	100	200	100	200	100	200	0.3	+175	+175	1500	20
Note				A ₁	A ₂	A ₁	A ₂	A ₁	A ₂	B				

NOTE A1 Average over a period greater than 100µsecs. A2 For a period less than 100µs.
B See derating curves.
C Commercial equivalent CV-7490 BFY17; CV-7491 BFY18.

CV 7490 - 91

Primary Electrical Characteristics

CV 7490-1

Characteristic	I_{CBO}	V_{CE} (sat)	V_{BE} (sat)	h_{fe}	f_T	C_{cb}	Noise Figure
Unit	nA	V	V		Mc/s	pF	dB
Min	-	-	-	40	200	-	-
Max	10	0.25	0.75	160	-	5.5	18
T_{case} °C	25	25	25	25	25	25	25
V_{CB} V	9	-	-	-	-	6	-
V_{CE} V	-	-	-	9	9	-	4.5
I_C mA	-	1	1	10	10	-	0.5
I_B mA	-	0.1	0.1	-	-	-	-
I_E mA	0	-	-	-	-	0	-
f Mc/s	-	-	-	1×10^{-3}	100	1	1×10^{-3}

Reliability Assurance Requirements: Under discussion

Requirements:

Marking As K1007, Section B.1.3.4

Quality Assurance Provisions

Destructive Tests The tests listed in Table 2, Group B Inspection, Sub-Group 2, 3 and 4 are considered destructive.

Group C Inspection This inspection shall be conducted on the initial lot, and thereafter every ninety days or every fifth lot, whichever occurs first.

Preparation for Delivery

Packaging The device shall be packed according to
K1007, Issue 3, Section A., 1.2.(c). AIS Size 6

Joint Service Catalogue Numbers

CV 7490 - 5960-99-037-3701
CV 7491 - 5960-99-037-3702

This specification has been prepared by, and the Qualification Approval
Authority is:-

Engineer-in-Chief
'S' Branch
Post Office, London.

TABLE 1. GROUP A INSPECTION

Examination or Test	Test Conditions		Insp. Level	Symbol	Limits		Units
	K1007/ NATO REF.	Specific Conditions			Min.	Max.	
<u>SUB GROUP 1</u> Visual and Mechanical Inspection	5-1	Excluding Physical Dimensions	I				
<u>SUB GROUP 2</u> Collector-Base Cut-off current (1)	7.2.5.1	$V_{CB} = 9V$ $I_E = 0$	II	I_{CB01}		10	nA
Collector-Base Cut-off current (2)	7.2.5.1	$V_{CB} = 40V$ $I_E = 0$		I_{CB02}		1	μA
Collector Emitter Cut-off current (1)	7.2.5.2	$V_{CE} = 9V$ $I_B = 0$		$I_{CE0(1)}$		50	nA
Transition Frequency		$I_C = 10 mA$ $V_C = 9V$ $f = 100 Mc/s (min)$		f_T	200		Mc/s
Output Capacitance	7.4.8.	$V_{CB} = 6V$ $I_E = 0$ $f = 1 Mc/s$		C_{ob}		5.5	pF
<u>SUB GROUP 3</u> Collector Emitter Saturation Voltage	7.3.3	$I_C = 1 mA$ $I_B = 0.1 mA$	I	$V_{CE(sat)}$		0.25	V

TABLE 1. GROUP A INSPECTION (Cont'd)

Examination or Test	Test Conditions		AQL %	Insp. Level	Symbol	Limits		Units
	K1007/ NATO Ref.	Specific Conditions				Min.	Max.	
SUB GROUP 3 (Cont'd) Base Emitter Saturation Voltage	7.3.3	$I_C = 1 \text{ mA}$ $I_B = 0.1 \text{ mA}$			$V_{BE} \text{ (sat)}$		0.75	V
	7.4.2	$I_C = 10 \text{ mA}$ $V_{CE} = 9V$ $f = 1 \text{ kc/s}$			h_{fe}	40	160	
Noise Factor	7.6.3	$I_C = 0.5 \text{ mA}$ $V_{CE} = 4.5V$ $f = 1 \text{ kc/s}$			N		18	dB
Emitter Base Cut-off Current	7.2.6	$V_{EB} = 3V$ $I_C = 0$			I_{EBO}		1	μA
SUB GROUP 4 Breakdown Voltage Collector to Emitter Collector Emitter Cut-off Current	7.2.5.1	$I_C = 10 \text{ mA}$ (see Note 2) $I_B = 0$ $V_{CE} = 9V$ $I_B = 0$ $T_{amb} = +150^\circ\text{C}$	4.0	IA	$V_{(BR)CEO}$	24		V
					$I_{CEO} \text{ (2)}$	100		μA

TABLE 2. GROUP B INSPECTION

Examination or Test	Test Conditions		AQL %	Insp. Level	Symbol	Limits		Units
	K1007/ NATO Ref.	Specific Conditions				Min.	Max.	
<u>SUB GROUP 1</u> Physical Dimensions	5.1	Check dimensions to drawings CV-A 10.3.2.2 and 10.4.2.2 (Note 1) CV-B 10.3.4 and 10.4.2.4	6.5	IC				
<u>SUB GROUP 2</u> Solderability Temperature Cycling Moisture Resistance	5.13 5.5 5.3	-55°C to +175°C	4.0	IA				
<u>SUB GROUP 3</u> Vibration Fatigue	5.15.1		4.0	IC				
<u>SUB GROUP 4</u> Lead Fragility	5.10.2	2 cycles	6.5	IA				
<u>SUB GROUP 5</u> Omitted								
<u>SUB GROUP 6</u> Omitted								
<u>SUB GROUP 7</u> High Temperature Life (Non Operating)	6.2.1 6.6.1.2.2	T _{stg} + 175°C Duration 1000 hrs	4.0	I Maximum 125 Devices				

TABLE 2. GROUP B INSPECTION (Cont'd)

Examination or Test	Test Conditions		Insp. Level	Symbol	Limits		Units
	K1007/ NATO Ref.	Specific Conditions			Min.	Max.	
<u>SUB GROUP 8</u> Operating Life	6.3 6.6.1.2.2	$V_{CB} = 20V$ MIN Duration 1000 hrs. T_{amb} may be at any single temperature between $+25^{\circ}C$ and $+125^{\circ}C$ with P_{tot} corresponding to that given on the derating curve Page 12.	IA				
<u>Post Test End</u> <u>Points for</u> <u>SUB GROUPS 2 to 8</u> <u>(inclusive)</u>							
Collector Base Cut-off Current	7.2.5.1	$V_{CB} = 9V$ $I_E = 0$		I_{CBO}	20		mA
Small Signal Short Circuit Forward Current Transfer Ratio	7.4.2	$I_C = 10$ mA $V_{CE} = 9V$ $f = 1$ kc/s		h_{fe}	35	180	

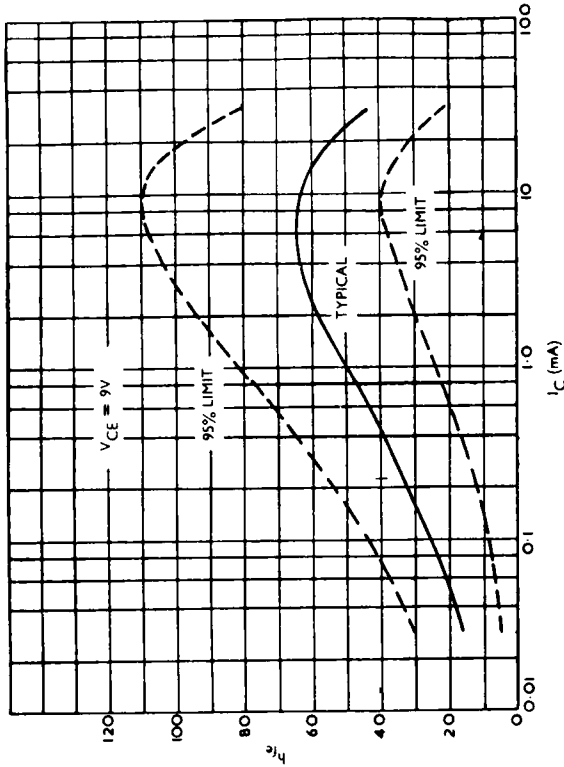
TABLE 3. GROUP C INSPECTION

Examination or Test	Test Condition		INSP. LEVEL	Symbol	Limits		Units
	K1007/ NATO Ref.	Specific Condition			Min.	Max.	
<u>SUB GROUP 1</u> Omitted							
<u>SUB GROUP 2</u> Shock	5.17.1	Non operating	IA				
<u>Post Test End</u> <u>Points for</u> <u>SUB GROUP 2</u> Collector Base Cut-off Current	7.2.5.1	$V_{CB} = 9V$ $I_E = 0$ $I_C = 10 mA$ $V_{CE} = 9V$ $f = 1 kc/s$		I_{CB0}	20		nA
Small Signal Short Circuit Forward Current Transfer Ratio				h_{fe}	35	180	

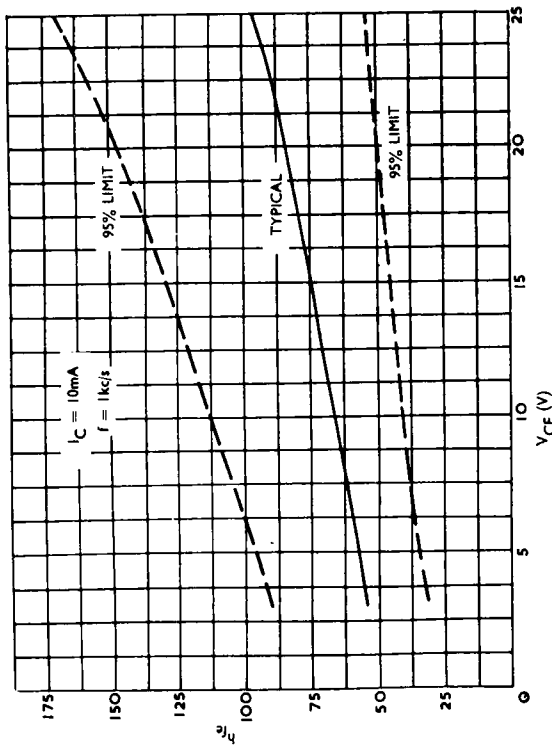
NOTES

1. Lead length 0.3 in. min.
2. 300 μ Sec. pulse; maximum duty cycle \neq

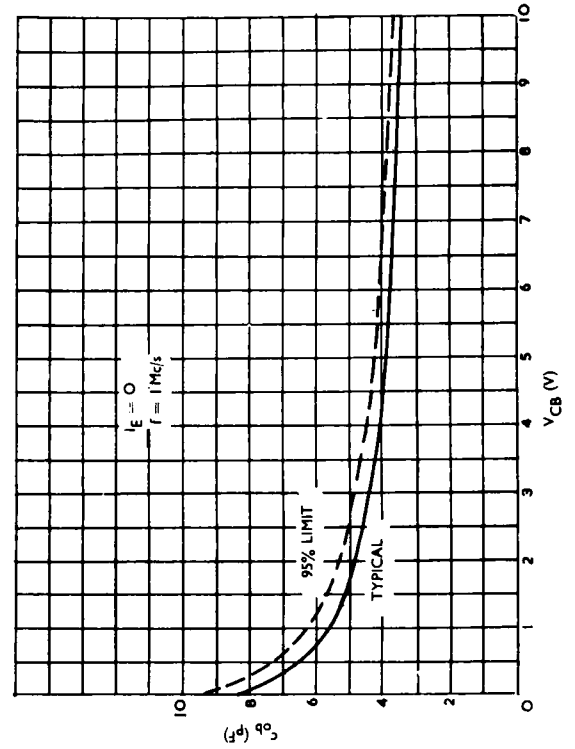
Small Signal Common Emitter Forward Current Transfer Ratio v. Collector Current



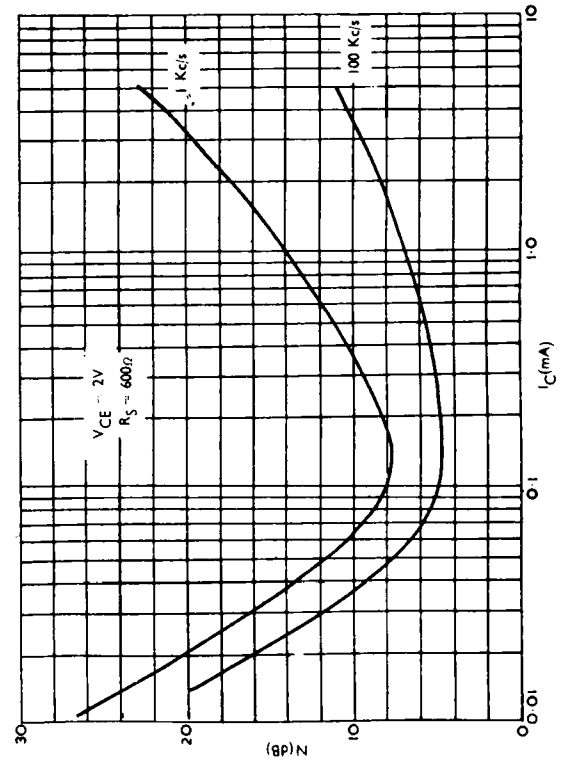
Small Signal Common Emitter Forward Current Transfer Ratio v. Collector Voltage



Common Base Output Capacitance v. Collector Voltage

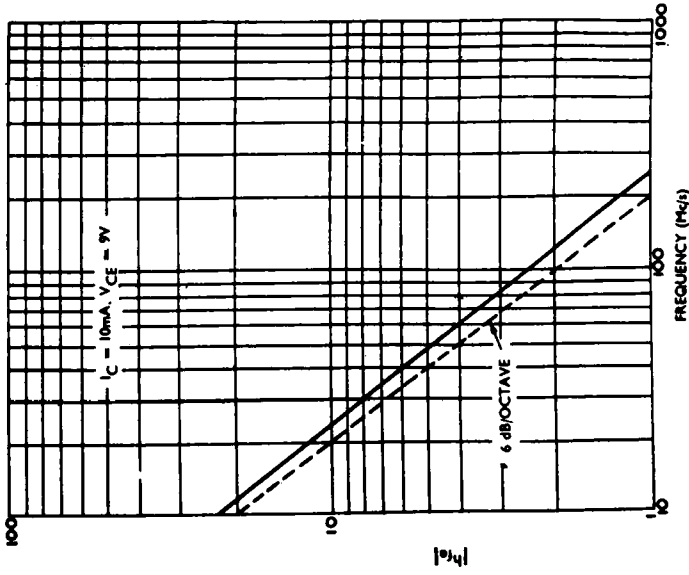


Typical Noise Factor v. Collector Current

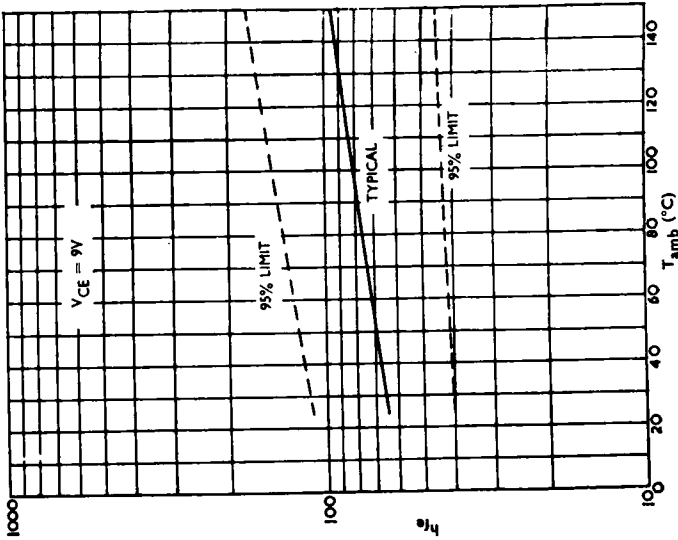


CV 7490-9I

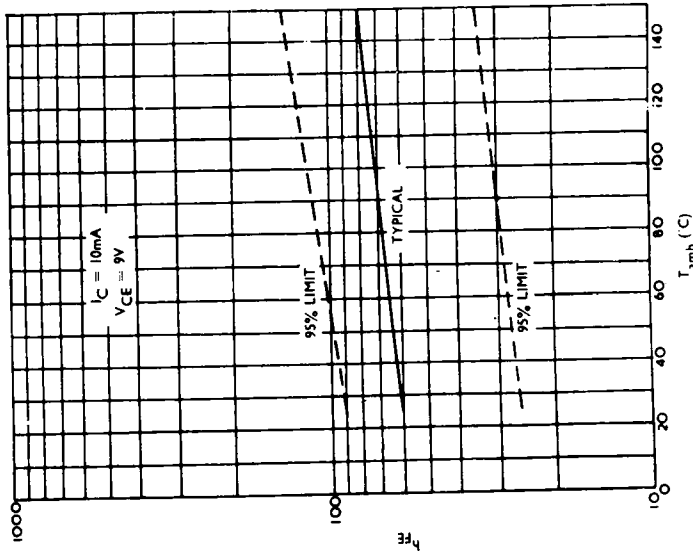
Typical Modulus of Small Signal Common Emitter Forward Current Transfer Ratio v. Frequency



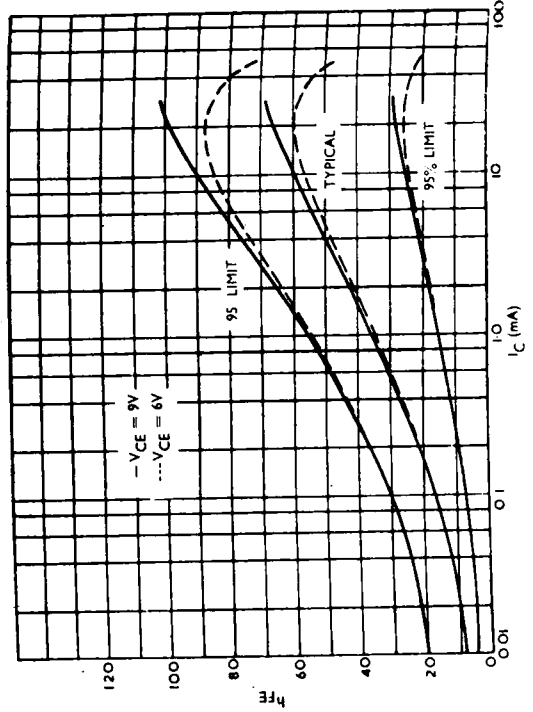
Small Signal Common Emitter Forward Current Transfer Ratio v. Temperature



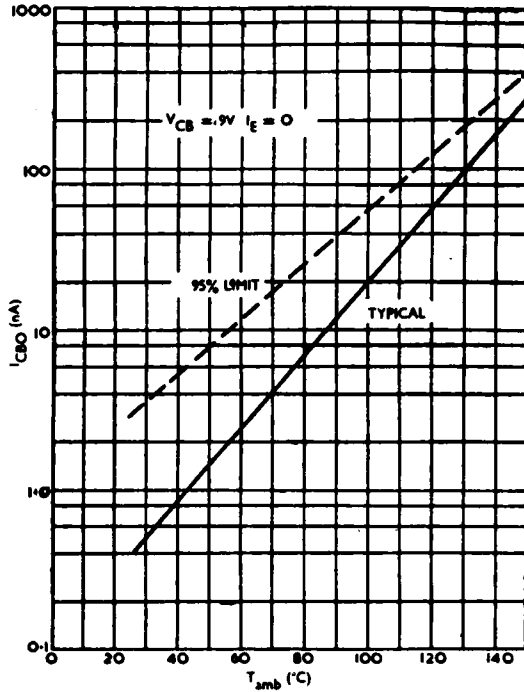
Large Signal Common Emitter Forward Current Transfer Ratio v. Temperature



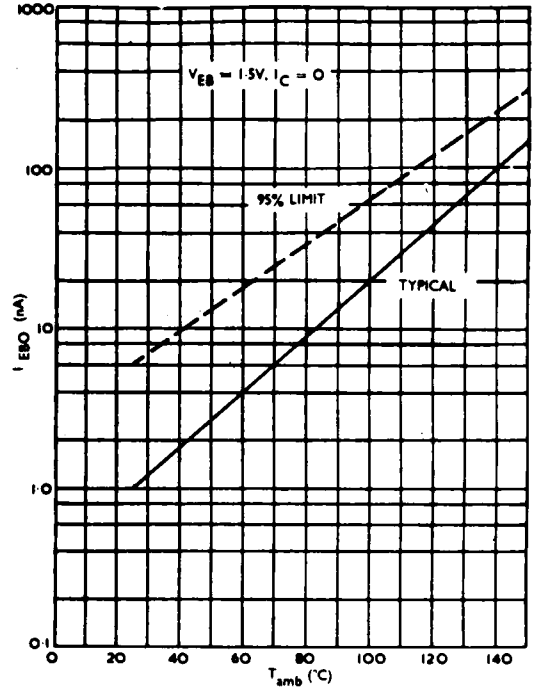
Large Signal Common Emitter Forward Current Transfer Ratio v. Collector Current



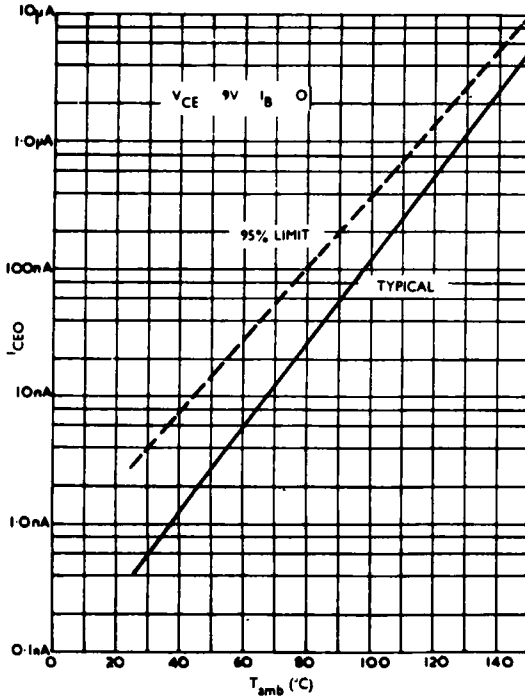
Collector-Base Cut-off Current v. Temperature



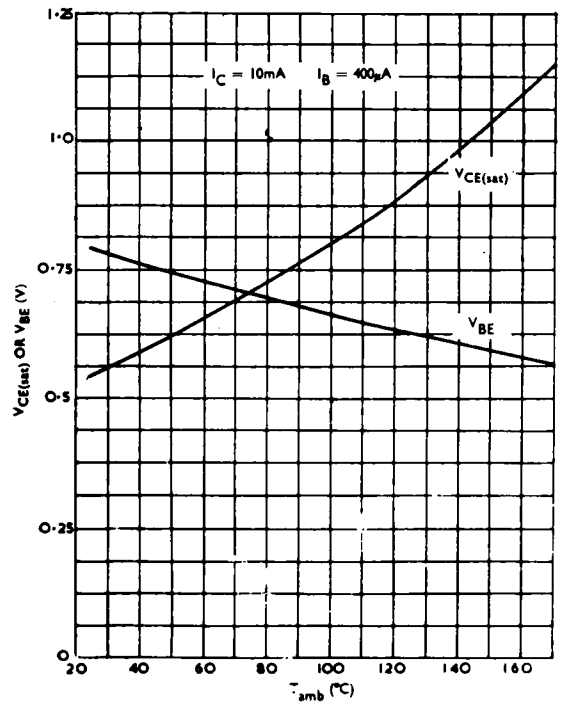
Emitter-Base Cut-Off Current v. Temperature



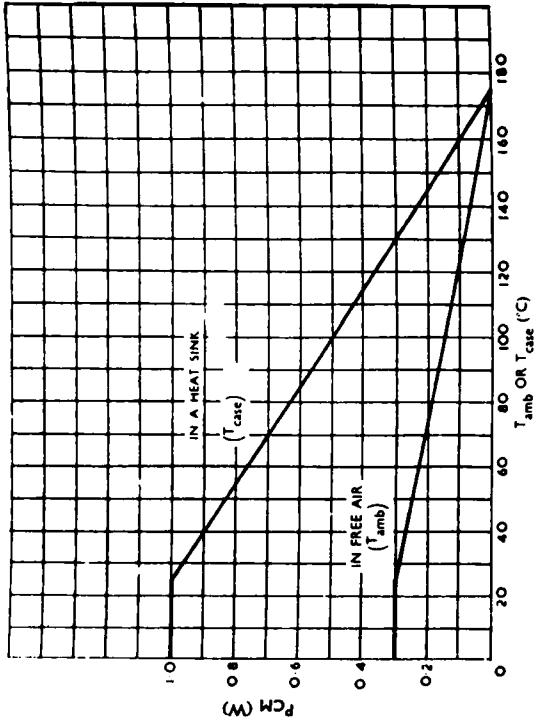
Collector-Emitter Cut-off Current v. Temperature



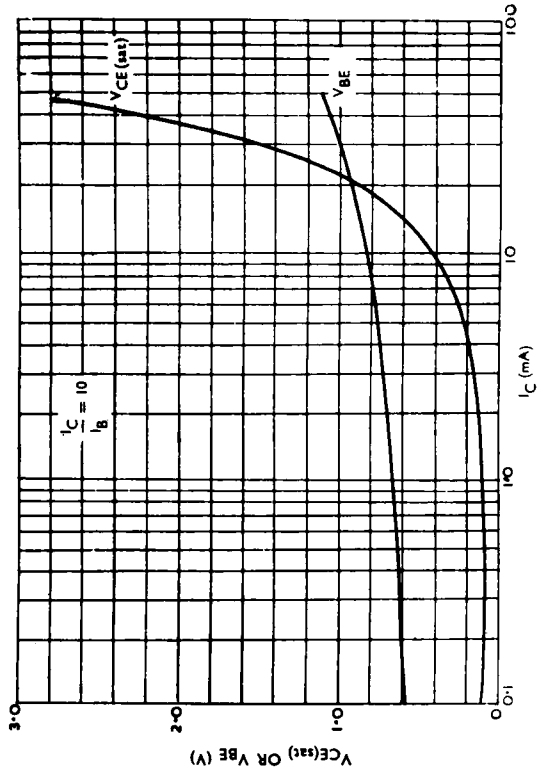
Typical Collector-Emitter Voltage and Base-Emitter Voltage v. Temperature



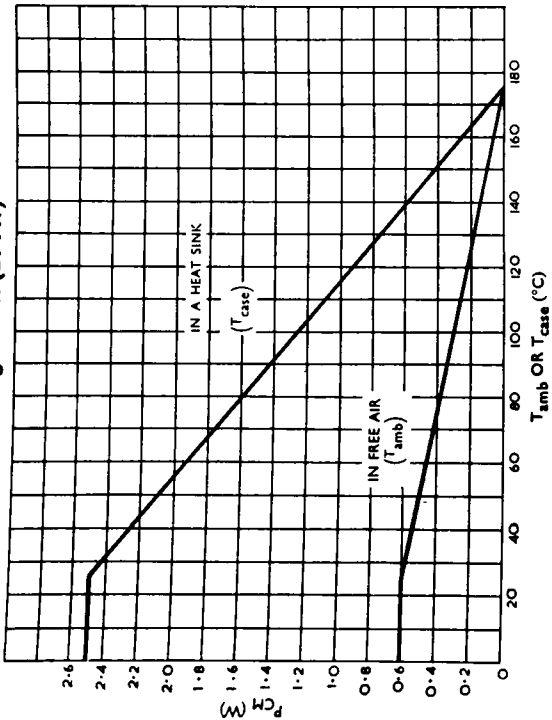
Derating Curves (BFY18)



Typical $V_{CE(sat)}$ and V_{BE} v. Collector Current



Derating Curves (BFY17)



Typical Contours of Constant Gain-Bandwidth Product, f_r

